

Integrated Device Technology, Inc. 6024 Silver Creek Valley Road, San Jose, CA 95138

# PRODUCT/PROCESS CHANGE NOTICE (PCN)

Product Affect IDT82P22	288, IDT82V2081, IDT82 082, IDT82V2042E, IDT	VT82P2282, IDT82P2 2V2041E, IDT82V20	284, □ 51E, □ □	Product Mark Back Mark Date Code Other ttachment:		ANGED DEVICES: (a) change as listed in
E-mail:	Lester.Wollman@idt.c	<u>om</u>				
<ul><li>□ Die Techn</li><li>□ Wafer Fab</li><li>□ Assembly</li><li>□ Equipment</li><li>□ Material</li><li>□ Testing</li></ul>	Material  Testing  Manufacturing Site  Data Sheet					
RELIABILITY/QUALIFICATION SUMMARY:  There is no change to the product quality and reliability performance.						
CUSTOMER ACKNOWLEDGMENT OF RECEIPT:  IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable.  IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.						
Customer:		_		Approval for	r shipments pr	ior to effective date.
Name/Date:			E-Ma	il Address:		
Title:			Phone	e # /Fax #:		
CUSTOMER	R COMMENTS:					
IDT ACKNO	OWLEDGMENT OF RE	CCEIPT:				
RECD. BY:			_ D	ATE:		



## PRODUCT/PROCESS CHANGE NOTICE (PCN)

### **ATTACHMENT I - PCN #: T-0603-01**

**PCN Type: Product Stepping Change** 

**Data Sheet Change:** None

**Detail of Change:** Product stepping changes to improve manufacturing efficiency. There is

no change in data sheet parameters and in the ordering part numbers.

See table below for means of distinguishing changed devices.

#### Table 1:

_	Date Code Prefix		
Device	From	To	
82P2281	Z	ZB	
82P2282	Z	ZB	
82P2284	ZB	ZC	
82P2288	ZB	ZC	
82V2081	Z	ZB	
82V2041E	Z	ZB	
82V2051E	Z	ZB	
82V2082	ZB	ZC	
82V2042E	ZB	ZC	
82V2052E	ZB	ZC	

#### **Qualification Data:**

Test Description	Test Method (Latest specs in effect)	Sample Size /# of Fails	Test Results
Operating Lifetest (Dynamic) 125°C@1000 Hrs	MIL-STD 883 Method 1005	77/0	77/0
HAST 130°C/85%RH Static Bias for 100 Hrs	EIA/JESD22-A110	45/0	45/0
Autoclave 121°C@168 Hrs@ATM, Saturated Steam	EIA/JESD22-A102	45/0	45/0
Temperature Cycle (Cond. B) -55°C/125°C, 1000 Cycles	MIL-STD 883 Method 1010	45/0	45/0
ESD: Human Body Model	MIL-STD 883 Method 3015	3/0	2,000V
ESD: Charged Device Model	JESD22-C101	3/0	500V
Latch-up	JESD78	10/0	10/0

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### **ATTACHMENT I - PCN #: T-0603-01**

### **Affected Part Number**

IDT Part Number	IDT Part Number	IDT Part Number	IDT Part Number
IDT82P2281PF	IDT82P2284BBG	IDT82V2042EPF	IDT82V2052EPFG
IDT82P2281PFG	IDT82P2288BB	IDT82V2042EPFG	IDT82V2081PP
IDT82P2282PF	IDT82P2288BBG	IDT82V2051EPP	IDT82V2081PPG
IDT82P2282PFG	IDT82V2041EPP	IDT82V2051EPPG	IDT82V2082PF
IDT82P2284BB	IDT82V2041EPPG	IDT82V2052EPF	IDT82V2082PFG